

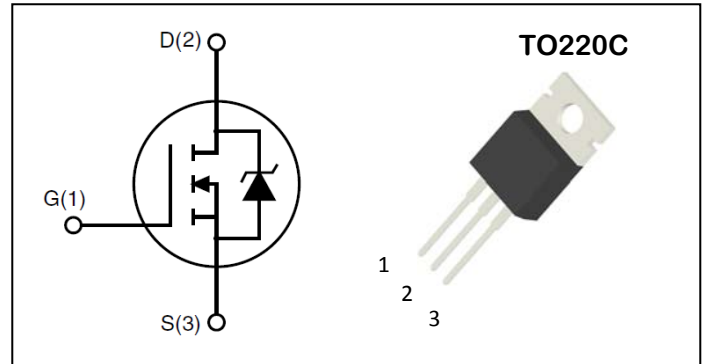
## N-Channel Enhancement Mode Field Effect Transistor

### PRODUCT SUMMARY

$V_{DSS}$	$I_D$	$R_{DS(ON)}$ (m $\Omega$ )
60V	75A	11.5m $\Omega$

### Features:

- Low Gate Charge for Fast Switching Application
- Low  $R_{DS(ON)}$  to Minimize Conductive Loss
- 100% EAS Guaranteed
- Optimized  $V_{(BR)DSS}$  Ruggedness
- Lead-Free, RoHS Compliant



### Description:

The ADM75N06 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

### Absolute Maximum Ratings ( $T_A = 25^\circ\text{C}$ unless otherwise specified )

Symbol	Parameter		Ratings	Unit
<b>Common Ratings</b>				
$V_{DSS}$	Drain-Source Voltage		60	V
$V_{GSS}$	Gate-Source Voltage		$\pm 20$	
$T_J$	Maximum Junction Temperature		175	$^\circ\text{C}$
$T_{STG}$	Storage Temperature Range		-55 to 175	$^\circ\text{C}$
$I_S$	Diode Continuous Forward Current	$T_C = 25^\circ\text{C}$	75	A
<b>Mounted on Large Heat Sink</b>				
$I_{DM}$	300 $\mu\text{s}$ Pulse Drain Current Tested <sup>(2)</sup>	$T_C = 25^\circ\text{C}$	300	A
$I_D$	Continuous Drain Current <sup>(1)</sup>	$T_C = 25^\circ\text{C}$	75	A
		$T_C = 100^\circ\text{C}$	50	A
$P_D$	Maximum Power Dissipation	$T_C = 25^\circ\text{C}$	110	W

### Thermal Characteristics

Symbol	Parameter	Ratings	Unit
$R_{thJC}$	Thermal resistance junction-case max <sup>(1)</sup>	1.36	$^\circ\text{C}/\text{W}$
$R_{thJA}$	Thermal resistance junction-ambient max <sup>(1)</sup>	62	$^\circ\text{C}/\text{W}$

## Electrical Characteristics (TA=25°C Unless Otherwise Noted)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
<b>On/off Characteristics</b>						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =250uA	60	68	--	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C	--	--	1	uA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =250uA	2	3	4	V
I <sub>GSS</sub>	Gate Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	--	--	±100	nA
R <sub>DS(ON)</sub>	Drain-Source On-state Resistance <sup>(2)</sup>	V <sub>GS</sub> =10V, I <sub>DS</sub> =30A	--	9.1	11.5	mΩ
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V,	--	2350	--	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =25V,	--	237	--	
C <sub>rss</sub>	Reverse Transfer Capacitance	Frequency=1MHz	--	205	--	
<b>Switching Characteristics</b>						
t <sub>d(ON)</sub>	Turn-on Delay Time	V <sub>DS</sub> =30V,	--	16	--	nS
t <sub>r</sub>	Turn-on Rise Time	I <sub>D</sub> =2A, V <sub>GS</sub> =10V,	--	10	--	
t <sub>d(OFF)</sub>	Turn-off Delay Time	R <sub>GEN</sub> =2.5 Ω	--	45	--	
t <sub>f</sub>	Turn-off Fall Time		--	12	--	
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =30V, V <sub>GS</sub> =10V,	--	50	--	nC
Q <sub>gs</sub>	Gate-Source Charge	I <sub>DS</sub> =30A	--	12	--	
Q <sub>gd</sub>	Gate-Drain Charge		--	16	--	
<b>Avalanche Characteristics</b>						
EAS	Single Pulse Avalanche Energy <sup>(3)</sup>	V <sub>DD</sub> =30V, L=0.5mH, V <sub>GS</sub> =10V, R <sub>g</sub> =25 Ω	450	--	--	mJ
<b>Diode Characteristics</b>						
V <sub>SD</sub>	Diode Forward Voltage <sup>(2)</sup>	I <sub>SD</sub> =30A, V <sub>GS</sub> =0	--	--	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>SD</sub> =75A, dI <sub>SD</sub> /dt=100A/μs	--	28	--	ns
q <sub>rr</sub>	Reverse Recovery Charge		--	49	--	nC

### NOTES:

1. Surface Mounted on FR4 Board, t ≤ 10 sec.
2. The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%
3. The Min. value is 100% EAS tested guarantee.

## Typical Performance Characteristics

Figure 1: On-Region Characteristics

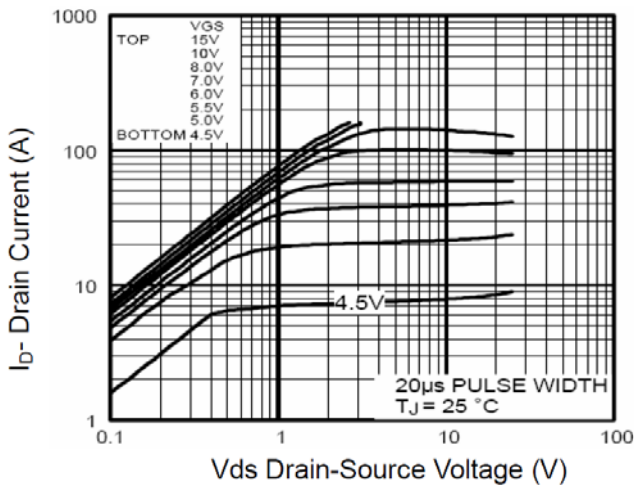


Figure 2: Transfer Characteristics

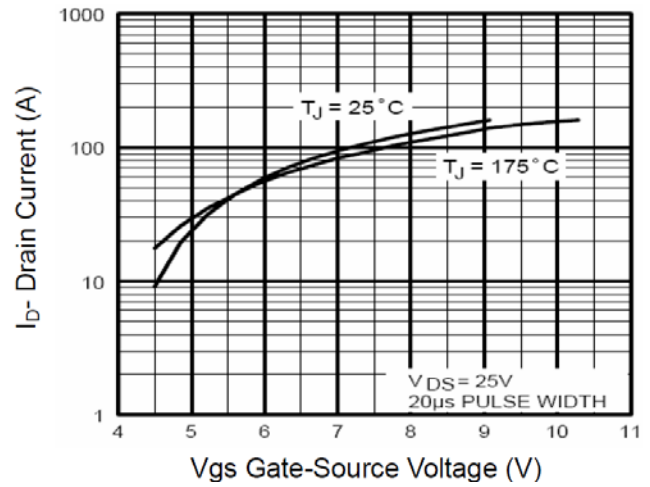


Figure 3: Rds(on)- Drain Current

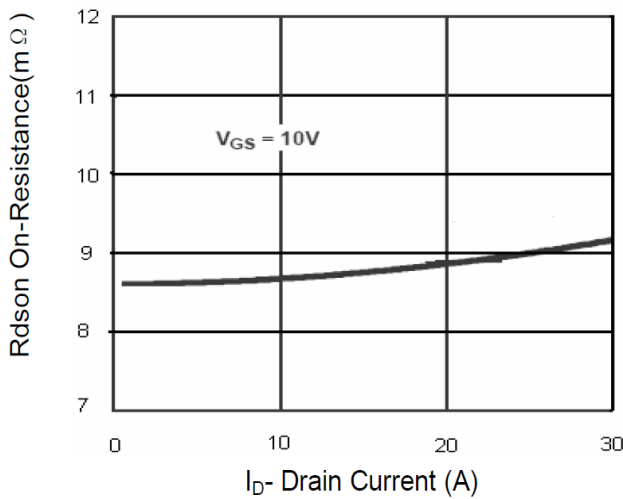


Figure 4: Rds(on)-Junction Temperature

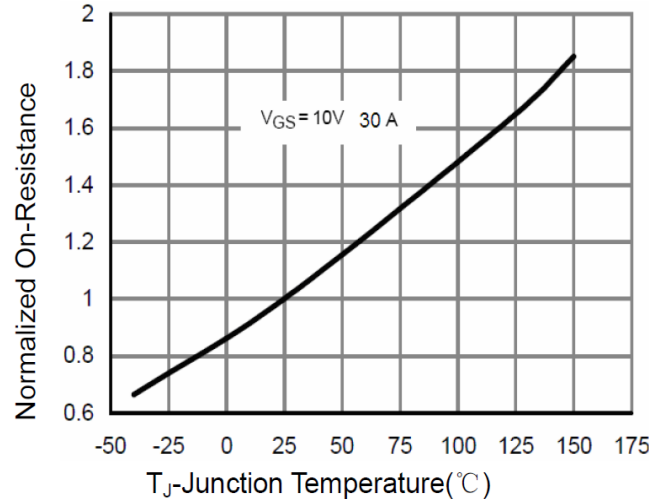


Figure 5: Source- Drain Diode Forward

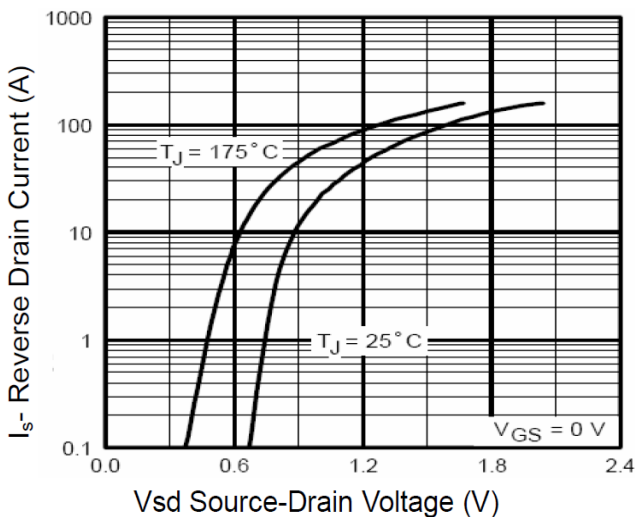


Figure 6: Gate Charge Characteristics

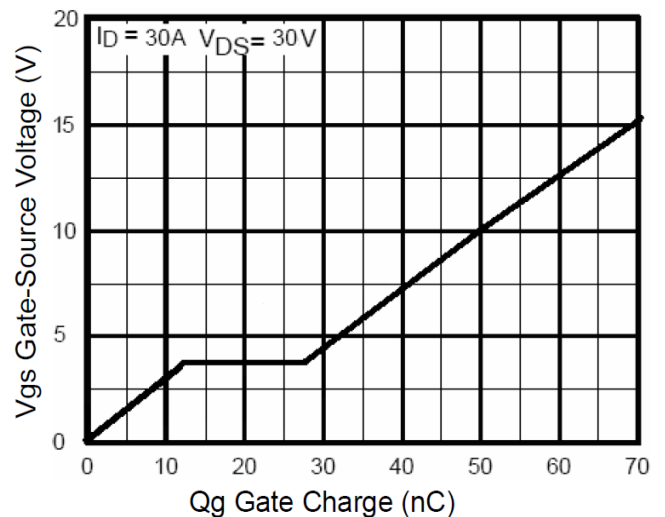


Figure 7: Capacitance vs Vds

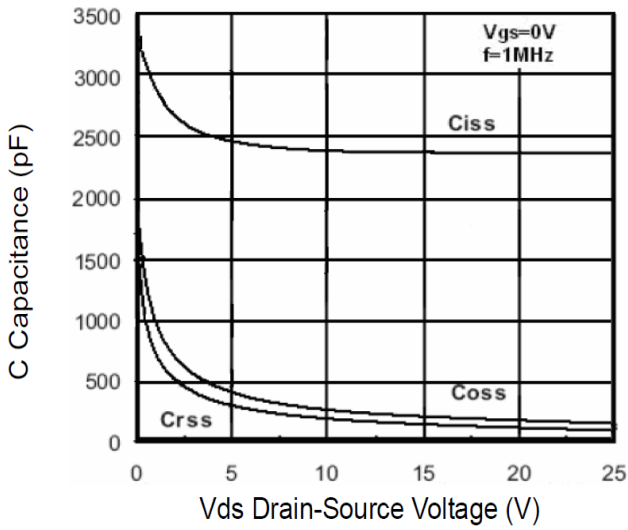


Figure 8: Safe Operation Area

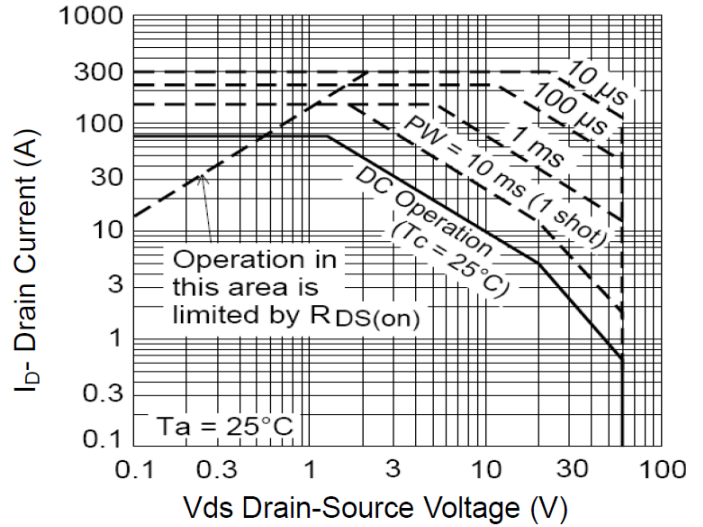


Figure 9: BV<sub>DSS</sub> vs Junction Temperature

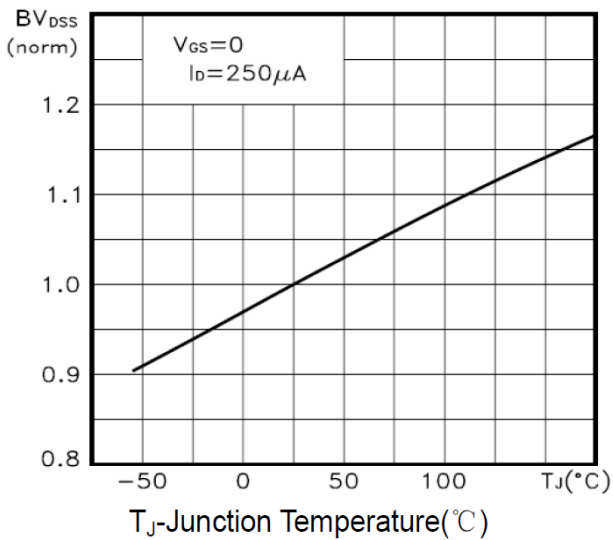


Figure 10: V<sub>GS(th)</sub> vs Junction Temperature

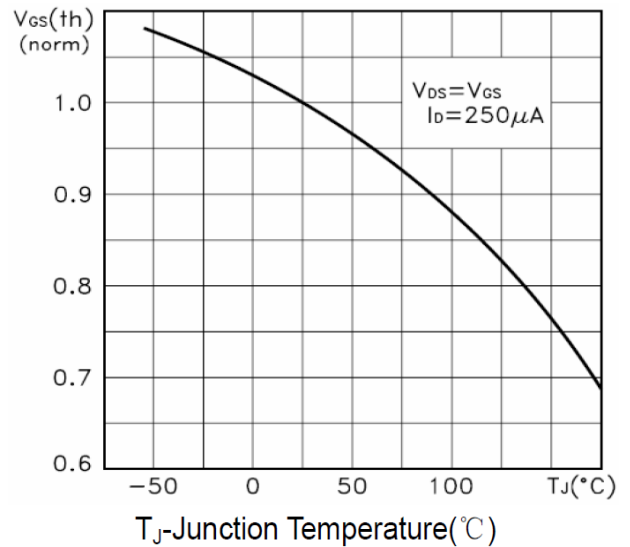
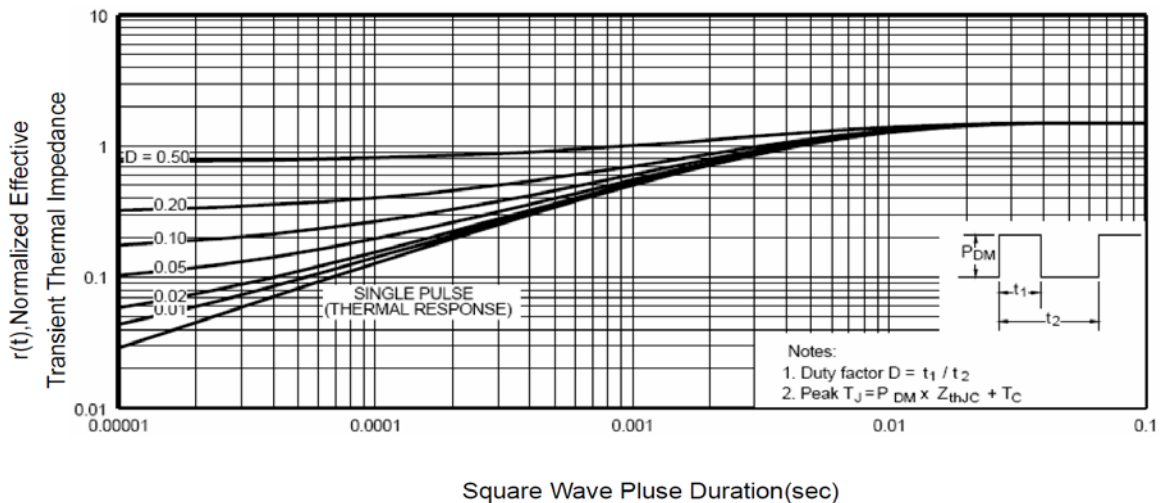
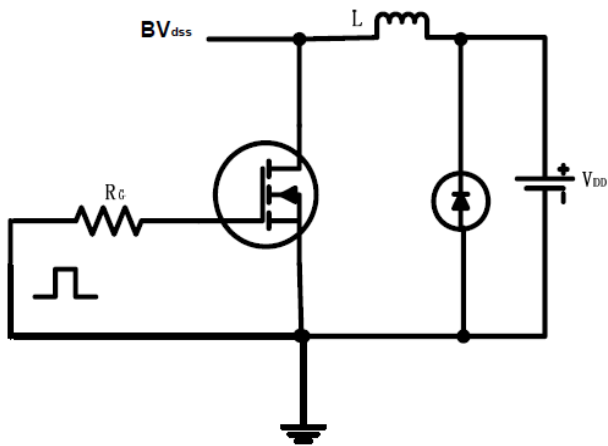


Figure 11: Normalized Maximum Transient Thermal Impedance

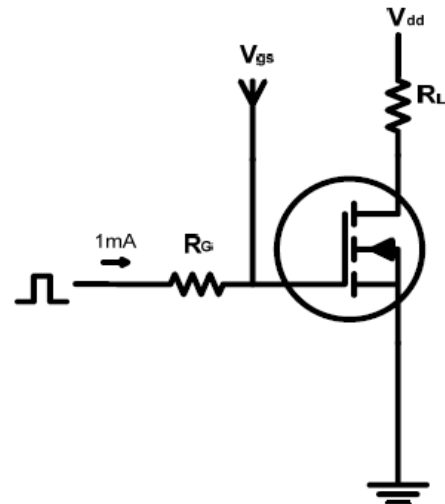


## Test circuits and Waveforms

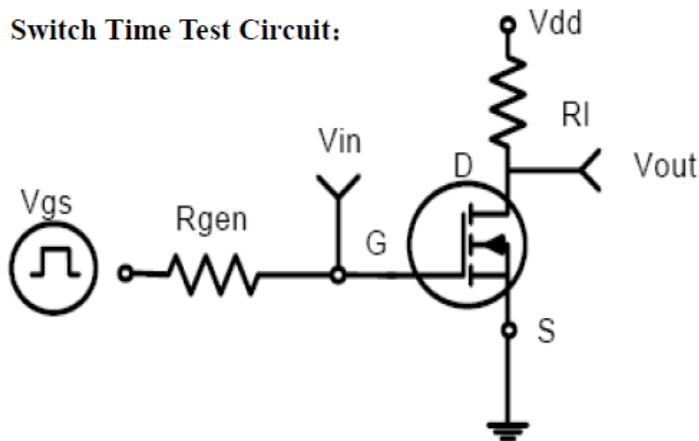
EAS test circuits:



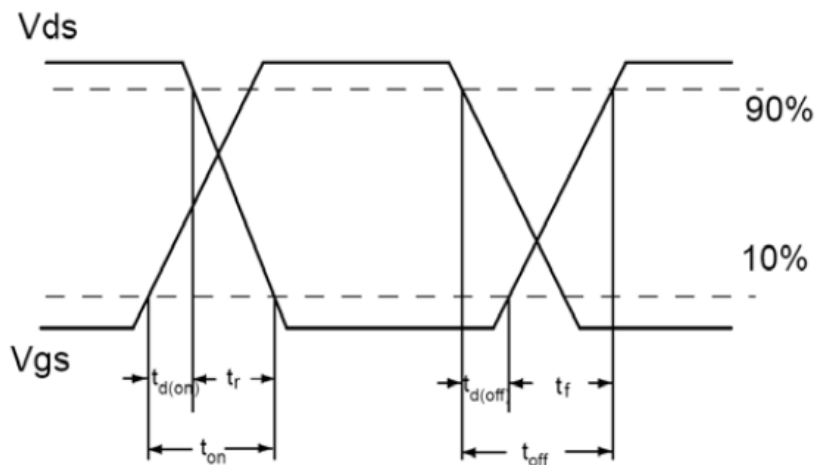
Gate charge test circuit:



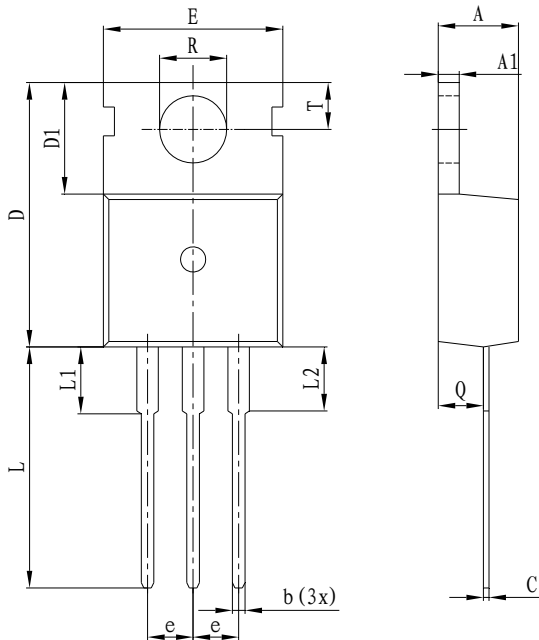
Switch Time Test Circuit:



Switch Waveforms:



**PACKAGE MECHANICAL DATA**  
**TO-220C Package Dimension**



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
e	2.54 TYP		0.099TYP	
A	4.10	4.70	0.161	0.185
A1	1.25	1.40	0.049	0.055
b	0.60	0.90	0.023	0.035
C	0.40	0.70	0.016	0.027
D	15.20	16.00	0.598	0.630
D1	5.90	6.60	0.232	0.259
E	9.70	10.30	0.382	0.405
L	12.80	15.00	0.504	0.590
L1	2.79	3.30	0.110	0.130
R	3.50	3.80	0.138	0.149
T	2.70	3.00	0.106	0.118
Q	2.20	2.60	0.086	0.102
L2		3.00		0.118

**Ordering information**

Part number	Package	Marking	Packing	Quantity
ADM75N06	TO-220C	ADM75N06	Tube	50pcs